

Gate control of InSb quantum wells with ALD gate dielectrics  
 ALD ゲート絶縁膜による InSb 量子井戸のゲート制御

The successful gate control of InSb two-dimensional systems is essential for extending our RD-NMR studies to the wider-range pump-and-probe experiments. They are also important to spintronics application of InSb systems including Majorana physics. To achieve this goal, high-quality Al<sub>2</sub>O<sub>3</sub> dielectrics were grown by atomic layer deposition (ALD) on InSb quantum wells. Magnetotransport measurements were carried out to clarify the characteristics of a gated InSb quantum wells. When we deposited Al<sub>2</sub>O<sub>3</sub> dielectrics on InSb top layer, the density of two-dimensional electrons in the QW was tuned by  $V_g$  but saturated at more negative  $V_g$ , probably due to hole accumulation at the interface. The better controllability without parallel conduction appears when we deposited Al<sub>2</sub>O<sub>3</sub> dielectrics directly on InAlSb top layer. The wider bandgap of Al<sub>0.1</sub>In<sub>0.9</sub>Sb top layer resulted in a linear, sharp, and non-hysteretic response of the 2DEG density to the gate bias as shown in Fig. 1. The obtained gate sensitivity reached to  $dn_s/dV_g = 3.9 \times 10^{15} \text{ m}^{-2}\text{V}^{-1}$ .

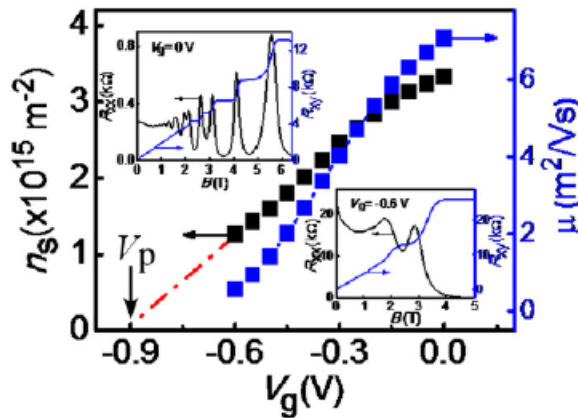


Fig. 1 Electron density  $n_s$  and mobility  $\mu$  of the InSb 2DEG as a function of gate bias  $V_g$  for the Al<sub>2</sub>O<sub>3</sub>-InSb device with the Al<sub>0.1</sub>In<sub>0.9</sub>Sb top layer. Insets show the magnetic-field ( $B$ ) dependent longitudinal resistance  $R_{xx}$  and Hall resistance  $R_{xy}$  at  $V_g = 0 \text{ V}$  and  $-0.6 \text{ V}$ .

Representative publications:

1. M. M. Uddin, H. W. Liu, K. F. Yang, K. Nagase, T. D. Mishima, M. B. Santos, and Y. Hirayama, Appl. Phys. Lett. 101, 233503 (2012).
2. M. M. Uddin, H. W. Liu, K. F. Yang, K. Nagase, K. Sekine, C. K. Gaspe, T. D. Mishima, M. B. Santos, and Y. Hirayama, Appl. Phys. Lett. 103, 123502 (2013).